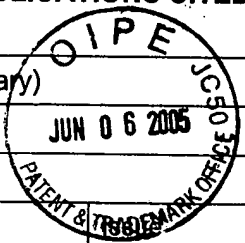


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. SEA/3369		Serial No.		
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)				Applicant Shih-Fu Lee		Confirmation No.:		
Examiner				Filing Date		Group		
<div style="text-align: center;">  </div>								
<b>U.S. Patent Documents</b>								
*Examiner Initial		Document Number	Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
	A1	6,618,215 B2	09-09-2003	Fung, et al.	360	31	03-06-2002	
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*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
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	B2						<input type="checkbox"/>	<input type="checkbox"/>
<b>OTHER ART</b>								
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.						
	C1	ECE Signals and Systems Fall, 2002, UMD, "Experiment 2: The Controls in the Spectrum Analyzer," 8 pages						
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<b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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<b>LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant Shih-Fu Lee	Confirmation No.:
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*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
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	B4						<input type="checkbox"/>	<input type="checkbox"/>
	B5						<input type="checkbox"/>	<input type="checkbox"/>
	B6						<input type="checkbox"/>	<input type="checkbox"/>

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	C5	<a href="http://whatis.techtarget.com/definition">http://whatis.techtarget.com/definition</a> , 2 pages
	C6	

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